

	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	66	(align\$5 adj30 (defect\$1 or (test\$5 adj20 result\$1)) adj30 (substrate\$1 or wafer\$1)) and (electron\$1 adj10 beam\$1)	US-PGPUB; USPAT; EPO; JPO; DERWEN T; IBM_TD B	2006/03/05 13:15
2	BRS	L2	0	(align\$5 adj30 (defect\$1 or (test\$5 adj20 result\$1)) adj30 (substrate\$1 or wafer\$1)) and (calculat\$5 adj30 position\$5 adj30 (substrate\$1 or wafer\$1) adj30 mark\$1) and (electron\$1 adj10 beam\$1)	US-PGPUB; USPAT; EPO; JPO; DERWEN T; IBM_TD B	2006/03/05 13:17
3	BRS	L3	24	(align\$5 adj30 (defect\$1 or (test\$5 adj20 result\$1)) adj30 (substrate\$1 or wafer\$1)) and (calculat\$5 adj30 position\$5 adj30 (substrate\$1 or wafer\$1)) and (electron\$1 adj10 beam\$1)	US-PGPUB; USPAT; EPO; JPO; DERWEN T; IBM_TD B	2006/03/05 13:17
4	BRS	L4	24	(align\$5 adj30 (defect\$1 or (test\$5 adj20 result\$1)) adj30 (substrate\$1 or wafer\$1)) and (calculat\$5 adj30 position\$5 adj30 (substrate\$1 or wafer\$1)) and (align\$5 adj30 mark\$1) and (electron\$1 adj10 beam\$1)	US-PGPUB; USPAT; EPO; JPO; DERWEN T; IBM_TD B	2006/03/05 13:38

	Type	L #	Hits	Search Text	DBs	Time Stamp
5	BRS	L5	0	(align\$5 adj30 (defect\$1 or (test\$5 adj20 result\$1)) adj30 (substrate\$1 or wafer\$1)) and (calculat\$5 adj30 position\$5 adj30 (substrate\$1 or wafer\$1)) and (align\$5 adj30 mark\$1) and (convert\$5 adj30 (defect\$1 or result\$1) adj30 position\$5 adj30 (substrate\$1 or wafer\$1)) and (electron\$1 adj10 beam\$1)	US- PGPUB; USPAT; EPO; JPO; DERWEN T; IBM_TD B	2006/03/05 13:20
6	BRS	L6	4	(align\$5 and (defect\$1 or (test\$5 adj20 result\$1)) and (substrate\$1 or wafer\$1) and calculat\$5 and position\$5 and (substrate\$1 or wafer\$1) and mark\$1 and (electron\$1 adj10 beam\$1)).clm.	US- PGPUB; USPAT; EPO; JPO; DERWEN T; IBM_TD B	2006/03/05 13:39